

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	169	(test adj structure) and (coupling capacitance\$2) and (multiplexer\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/03/08 17:02
L2	159	(test adj structure) and (coupling capacitance\$2) and (process parameter\$2) and (multiplexer\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/03/08 17:13
L3	1	((test adj structure) and (coupling capacitance\$2) and (process parameter\$2) and (multiplexer\$2)). CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/03/08 17:04
L4	1	((test adj structure) and (coupling adj capacitance\$2) and (process parameter\$2) and (multiplexer\$2)). CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/03/08 17:11
L5	1	(test adj structure) and (coupling adj capacitance\$2) and (process adj parameter\$2) and (multiplexer\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/03/08 17:04
L6	5615	324/765	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/03/08 17:09
L7	45	(324/765).cccls. and (coupling capacitance\$2) and (process adj parameter\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/03/08 17:10
L8	45	(324/765).cccls. and (coupling capacitance\$2) and (process adj parameter\$2) and (test structure\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/03/08 17:10
L9	13	(324/765).cccls. and (coupling capacitance\$2) and (process adj parameter\$2) and (test adj structure\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/03/08 17:11

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L10	0	(324/765).ccls. and (coupling adj capacitance\$2) and (process adj parameter\$2) and (test adj structure\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/03/08 17:11
L11	0	(324/765).ccls. and ((test adj structure) and (coupling adj capacitance\$2) and (process parameter\$2) and (multiplexer\$2))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/03/08 17:12
L12	1	(test adj structure) and (coupling adj capacitance\$2) and (process adj parameter\$2) and (multiplexer\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/03/08 17:13
S1	2486	716/4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/03/08 15:49
S2	1924	716/5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/03/08 15:48
S3	55	(716/4).ccls. and (coupling capacitance\$2) and (process adj parameter\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/03/08 17:09
S4	48	(716/5).ccls. and (coupling capacitance\$2) and (process adj parameter\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/03/08 15:51
S5	154	("716"/\$).ccls. and (coupling capacitance\$2) and (process adj parameter\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/03/08 15:52
S6	9327	(coupling capacitance\$2) and (process adj parameter\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/03/08 15:57
S7	211	(test adj structure) and (coupling capacitance\$2) and (process adj parameter\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/03/08 15:59

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S8	52	(test adj structure) and (coupling capacitance\$2) and (process adj parameter\$2) and (conductor and plate\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/03/08 17:01
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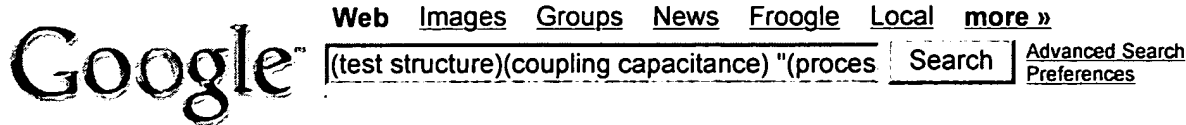
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